

Q14 Q13 Q12 Q11 Q10 Q9 Q8 Q7 Q6 Q5 Q4 Q3 Q2 Q1 Q0

RAMs lengthen output delays

by Vittal Rao

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Though output signals may be delayed slightly with a simple shift register, delays of longer duration require a disproportionately and often prohibitively larger number of such devices. However, this design uses a pair of random-access memories and a handful of integrated circuits to program a precise and accurate delay of up to 4,096 times the input clock pulse period into input data. The delay may be lengthened by using more counters and replacing the 4-K RAM with an 8-K RAM.

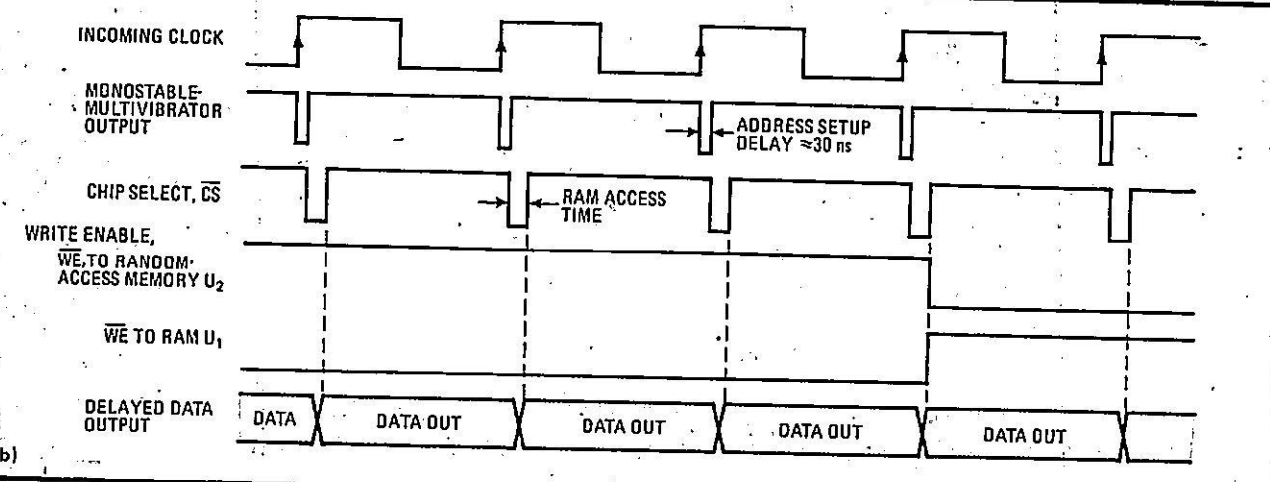
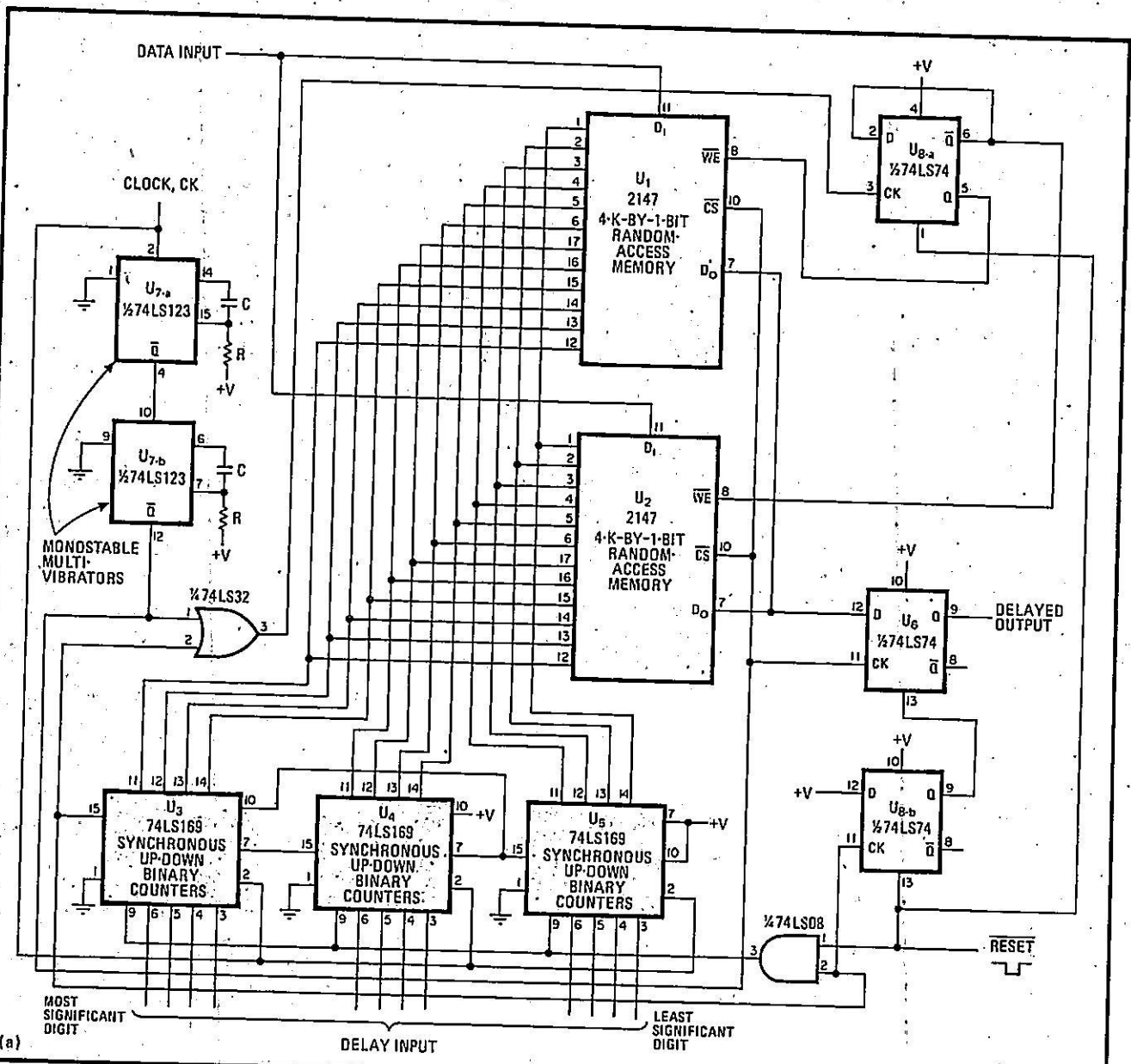
The desired time delay introduced by the circuit (a) is

given by $T_d = N \times T$, where N is the multiplier number set by the RAM's delay input and T is the period of the input clock. The delay input is loaded into the address generator comprising synchronous down counters U_1 through U_3 . For every incoming clock pulse (b), the counters decrement and generate an address for the data that is written.

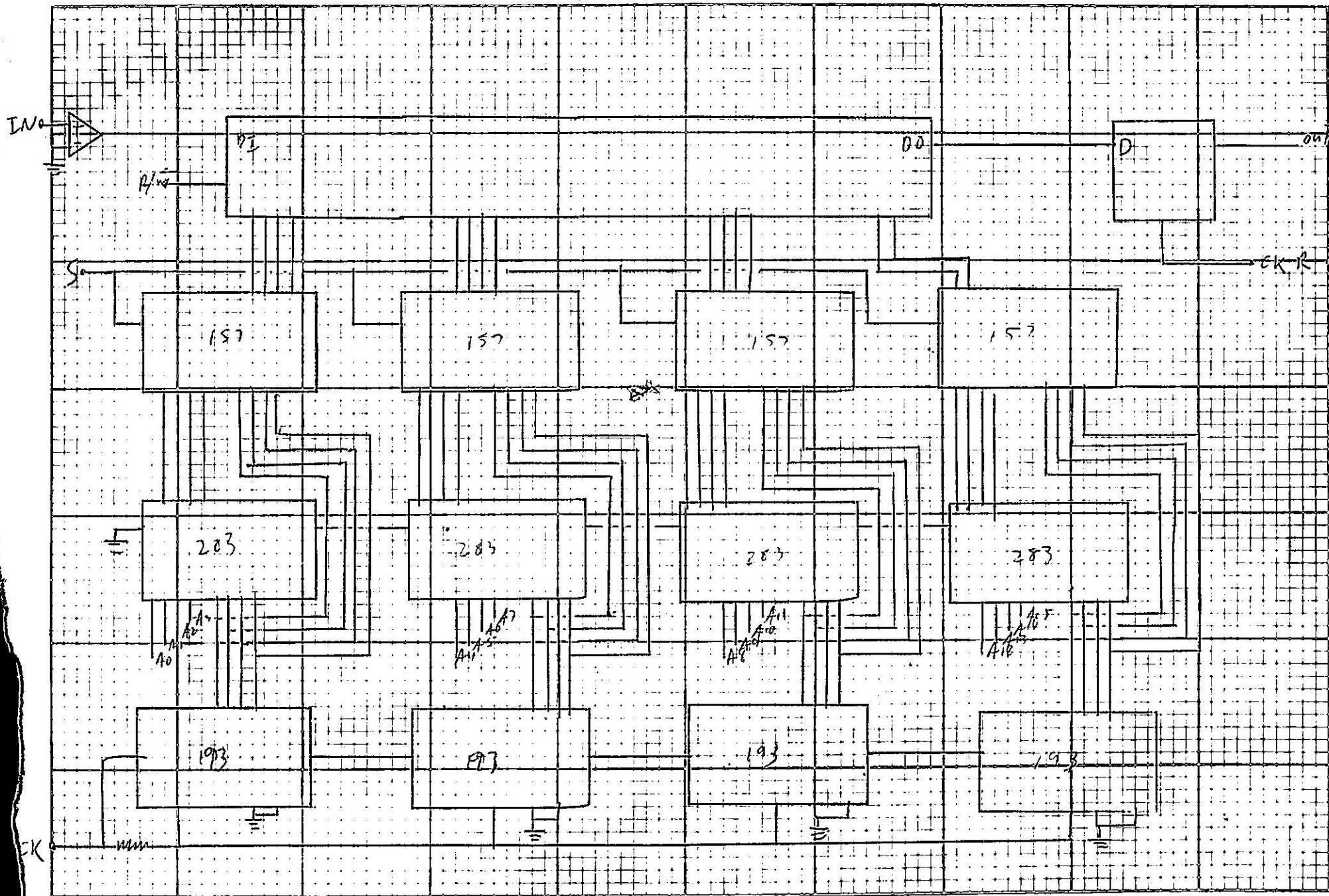
All incoming data that is written into RAM U_1 is simultaneously read from RAM U_2 . This operation continues until the counters reach 000, thereby introducing a delay that is proportional to delay-input number N . When the counters reach 000, the delay input is once again loaded into the counters automatically, and the incoming data is now written into U_2 and simultaneously read from U_1 .

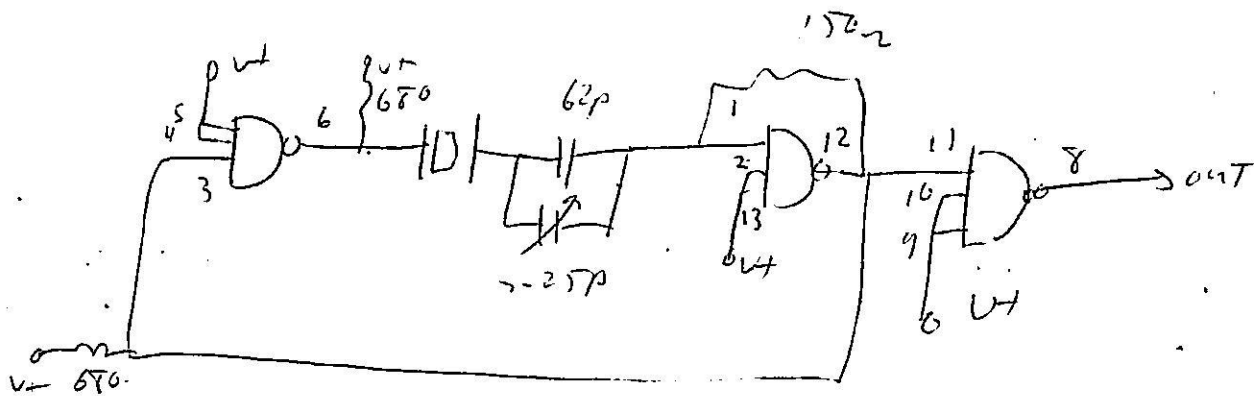
For this configuration, the maximum size of delay input N is 4,096 and is determined by the bit capacity of the memory used. The input N can be increased by using a higher-capacity RAM and more counters. □

Electronics/April 7, 1983

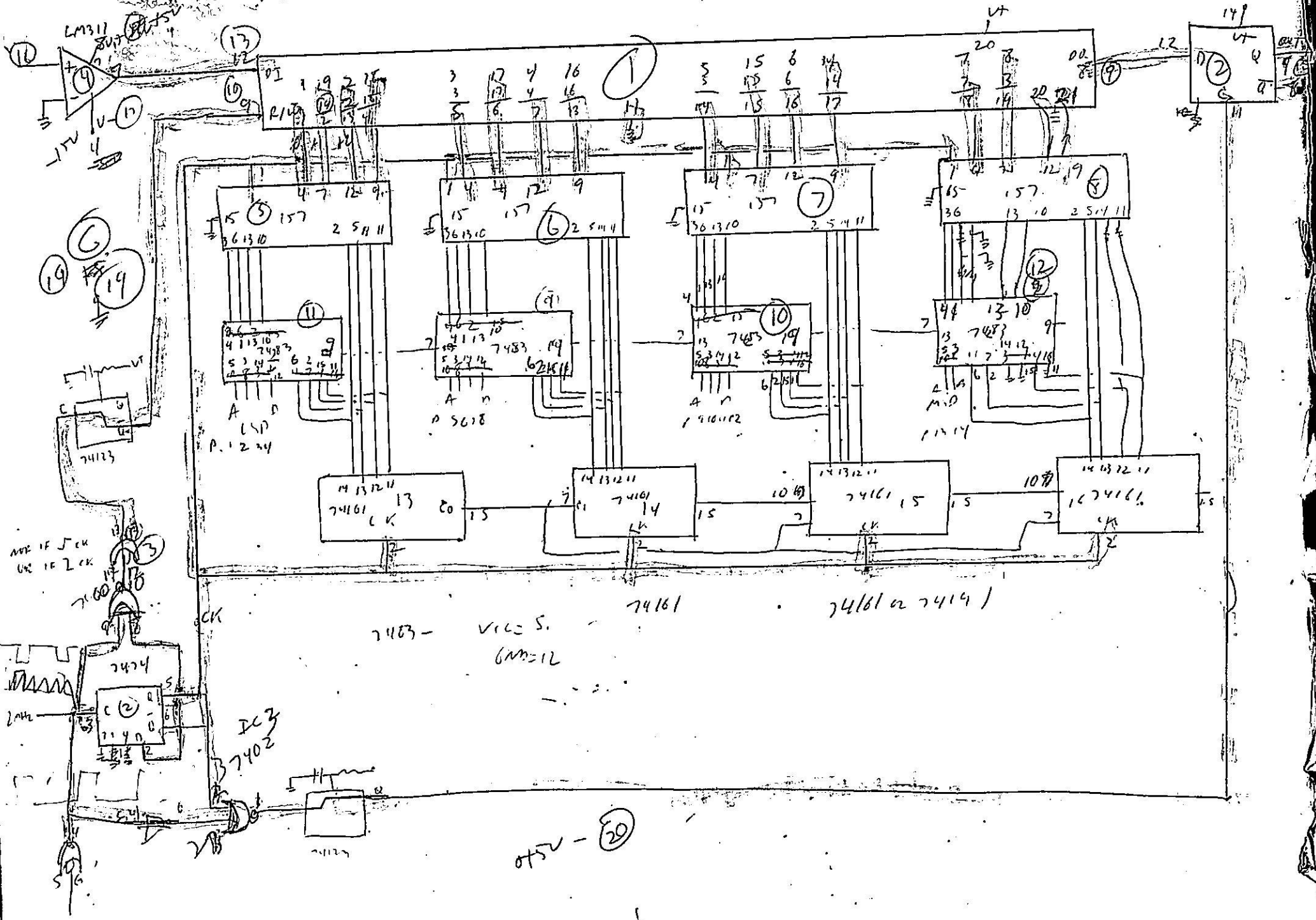


Delay. This digital circuit (a) delays incoming data by an amount proportional to delay input N , which is loaded into the address generator consisting of counters U_3 through U_5 . The resultant delay introduced is given by $T_d = N \times T$, where T is the period of the clock input. Because a 4-K-by-1-bit RAM is used, the maximum value of N is 4,096. The timing diagram (b) shows waveforms for read, write, and latch operations.





vis Em6riv. zip



7403 - VCC 5.
GND=12

74161

74161 or 74141

0.5V - 20

IC 3
7402

NOTE IF 5 CK
OR 16 2 CK

7400

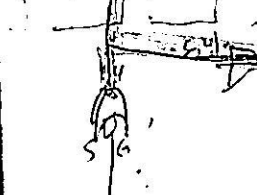
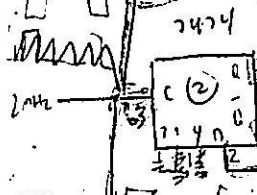
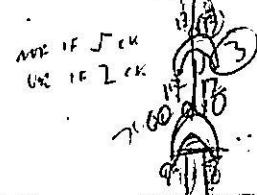
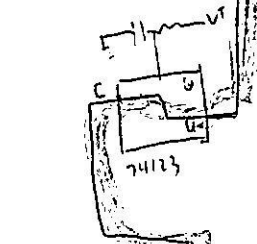
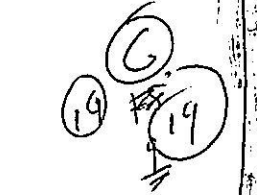
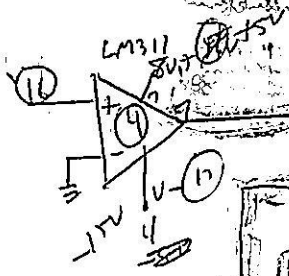
CK

20M

5.4V

5.6

74123



b.c.d.-to-binary converter

The circuit described by Falko Kuhnke in October Circuit Ideas is unduly complicated. Conversion can be effected using just a pair of 4008 i.c.s, rewriting

$$10X_{10} + X_1 \text{ as } 8X_{10} + 2X_{10} + X_1.$$

Multiplication by eight and two in binary requires only shifting and this can be hard wired.

N. G. de Mattos-Shiple
London EC4

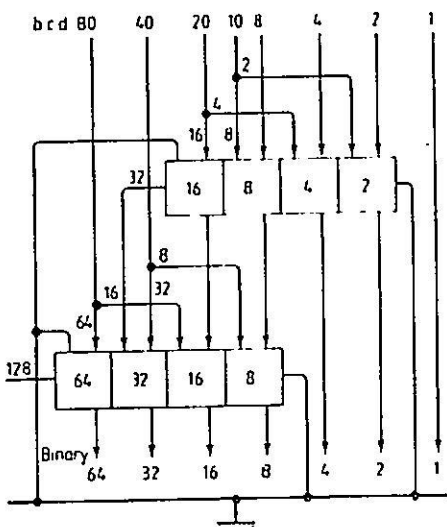


Fig. 1

The circuit described by F. Kuhnke can be simplified if we take into account that the b.c.d. numbers 10, 20, 40 and 80 may be split up into powers of 2, as $2+8$, $4+16$, $8+32$, $16+64$. If these values are added, together with the 1, 2, 4 and 8 inputs in a parallel adder, the output is a binary-weighted word with 64 as the highest value. The idea may be expanded to higher b.c.d. values, 100 to 800, 1000 to 8000, etc. as shown in my publication: "The conversion of b.c.d. words into binary numbers", *Microelectronics Journal*, vol. 11, no. 2, pages 29 to 34.

For comparison, the conversion of the numbers 1 to 99 is shown in Fig. 1. Only two i.c.s with four full adders (7483) each are needed.

C. van Holten
Technische Hogeschool, Delft

Binary output								b c d	
2^7	2^6	2^5	2^4	2^3	2^2	2^1	2^0	Value	Input
0	0	0	0	0	0	0	0	1	11
0	0	0	0	0	0	0	1	2	12
0	0	0	0	0	0	1	0	4	13
0	0	0	0	0	1	0	0	8	14
0	0	0	0	1	0	0	0	10	21
0	0	0	1	0	0	0	0	20	22
0	0	0	1	0	1	0	0	40	23
0	0	1	0	1	0	0	0	80	24
0	0	1	1	0	0	0	0	100	31
0	0	1	1	0	1	0	0	200	32
0	1	1	0	0	1	0	0	400	33
1	1	0	0	1	0	0	0	800	34

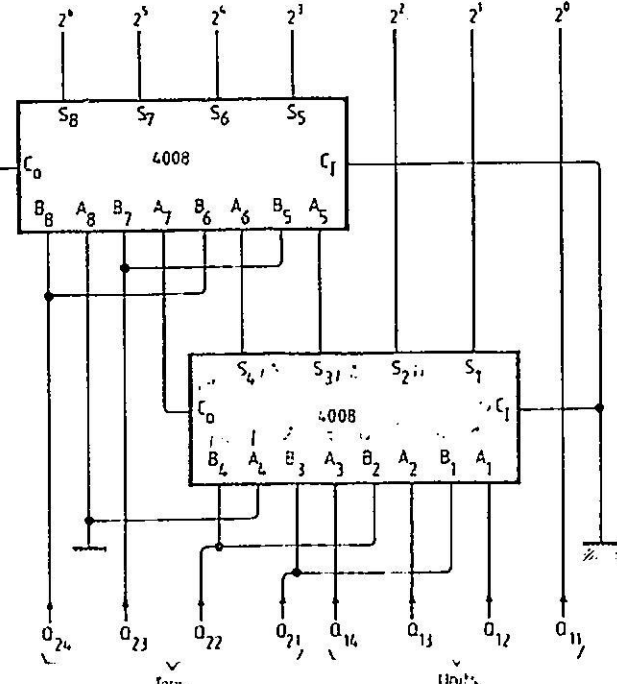
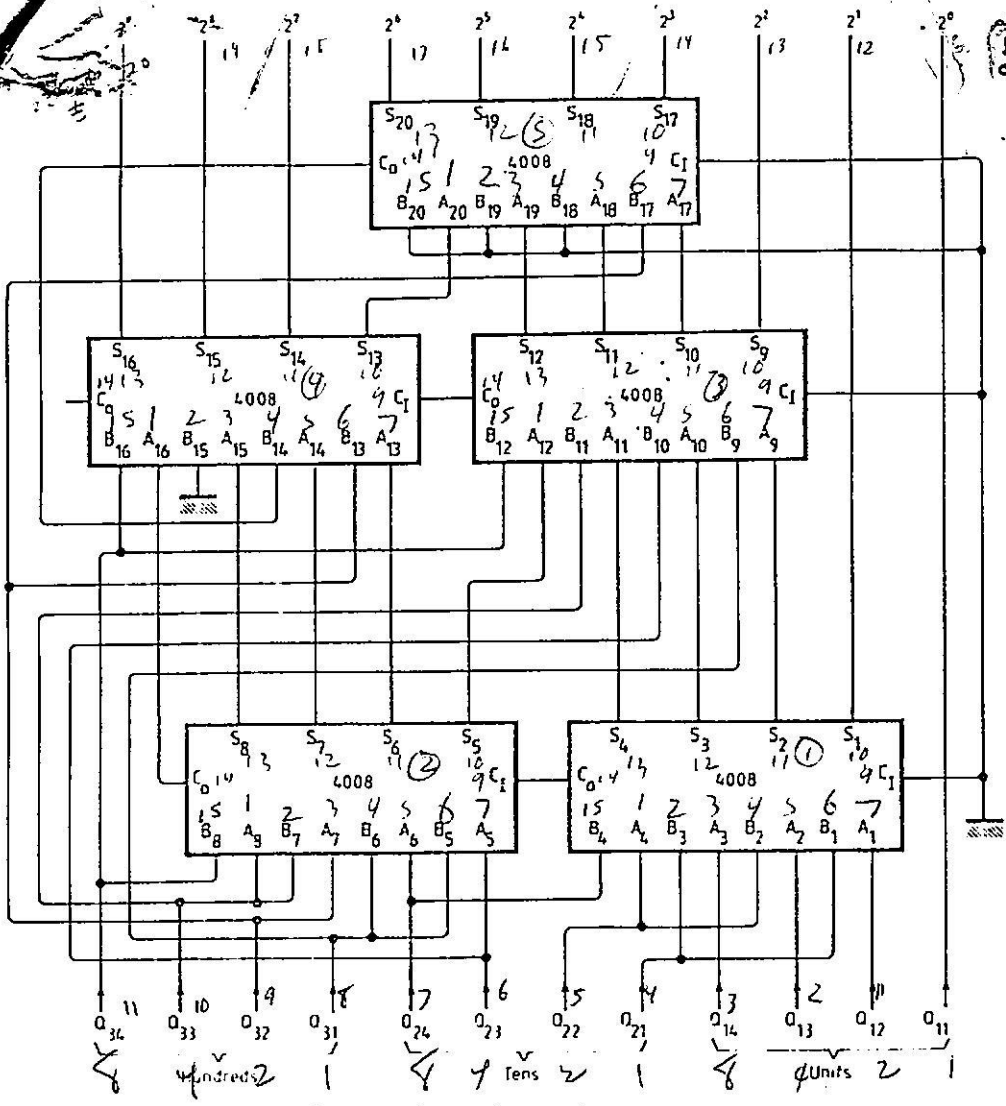


Fig. 2

The clue to the simplicity of Fig. 2. circuit is to be found in the table and the philosophy may be extended to derive a three decade converter.

The table shows the binary representation of the b.c.d. outputs from units, tens and hundreds counters. To obtain a binary representation of any decimal value in the range 000 to 999 it is only necessary to add the binary columns together of the appropriate rows, e.g. the binary representation of 647 may be obtained by adding the binary columns of rows Q11, Q12, Q13 (=7) to Q21 (=40) to Q32 and Q33 (=600). The maximum number of bits that need to be added together for a two-decade converter is three (see binary column 2^3). For a three-decade converter the maximum number is thus four

(again, see binary column 2^3). Fig. 3 illustrates a three-decade converter using five four-bit full adder i.c.s
A. J. Ewins
North Harrow

HM6287H Series

65536-Word × 1-Bit High Speed CMOS Static RAM

The Hitachi HM6287H is a high speed 64K static RAM organized as 64-kword × 1-bit. It realizes high speed access time (25/35 ns) and low power consumption, employing CMOS process technology and high speed circuit designing technology. It is most advantageous for the field where high speed and high density memory is required, such as the cache memory for main frame or 32-bit MPU. The HM6287H packaged in a 300-mil plastic DIP and SOJ, is available for high density mounting.

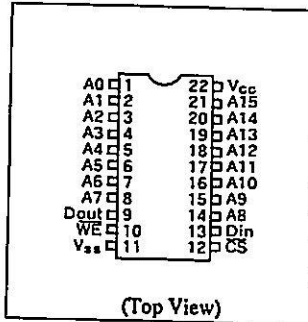
Low power version retains the data with battery back up.

Features

- Single 5 V supply and high density 22-pin DIP and 24-pin SOJ
- High speed: Fast access time 25/35 ns (max)
- Low power
 - Operation: 300 mW (typ)
 - Standby: 100 μW (typ)
- Completely static memory
 - No clock or timing strobe required
- Equal access and cycle times
- Directly TTL compatible: All inputs and outputs

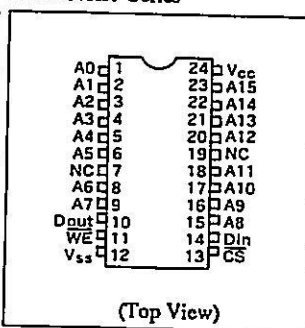
Pin Arrangement

HM6287HP Series



(Top View)

HM6287HJP Series

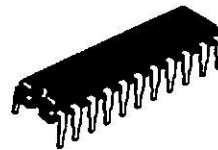


(Top View)

Ordering Information

Type No.	Access Time	Package
HM6287HP-25	25 ns	300-mil
HM6287HP-35	35 ns	22-pin
HM6287HLP-25	25 ns	plastic DIP
HM6287HLP-35	35 ns	(DP-22NB)
HM6287HJP-25	25 ns	300-mil
HM6287HJP-35	35 ns	24-pin SOJ
HM6287HLJP-25	25 ns	(CP-24D)
HM6287HLJP-35	35 ns	(CP-24D)

HM6287HP Series



(DP-22NB)

HM6287HJP Series

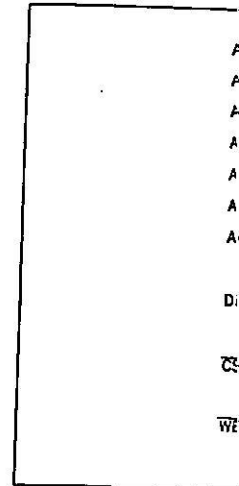


(CP-24D)

Pin Description

Pin Name	Function
A0 - A15	Address
Din	Input
Dout	Output
CS	Chip select
WE	Write enable
Vcc	Power supply
Vss	Ground

Block diagram



Function Table

CS	WE
H	x
L	H
L	L

Note: x: H or L

Absolute Maximum F

Item
Voltage on any pin relative to Vss
Power dissipation
Operating temperature
Storage temperature
Storage temperature under bias

Note: *1. Vr min = -2.0 V f

Recommended DC Op

Item
Supply voltage
Input high (logic 1) voltage
Input low (logic 0) voltage

Note: *1. VL min = -2.0 V f

Static b.c.d.-to-binary converter

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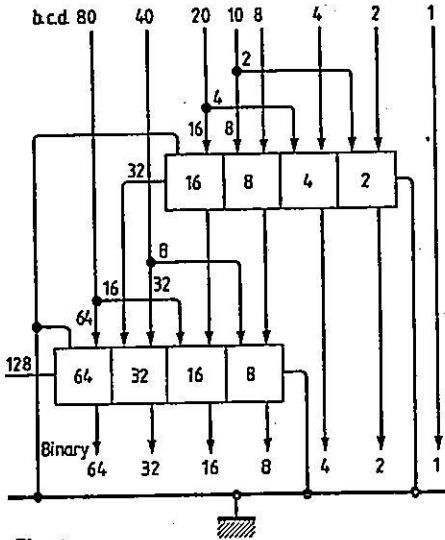


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0	0	0	0	0	0	0	0	0	1	1	11
0	0	0	0	0	0	0	0	1	0	2	12
0	0	0	0	0	0	0	1	0	0	4	13
0	0	0	0	0	1	0	0	0	0	8	14
0	0	0	0	0	1	0	1	0	0	10	21
0	0	0	0	1	0	1	0	0	0	20	22
0	0	0	1	0	1	0	0	0	0	40	23
0	0	1	0	1	0	0	0	0	0	80	24
0	0	1	1	0	0	1	0	0	0	100	31
0	0	1	1	0	0	1	0	0	0	200	32
0	1	1	0	0	1	0	0	0	0	400	33
1	1	0	0	1	0	0	0	0	0	800	34

Fig. 3

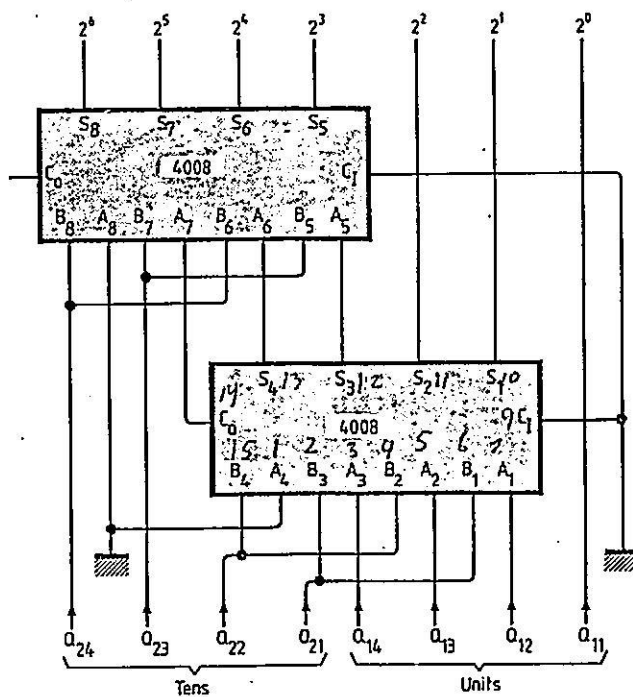
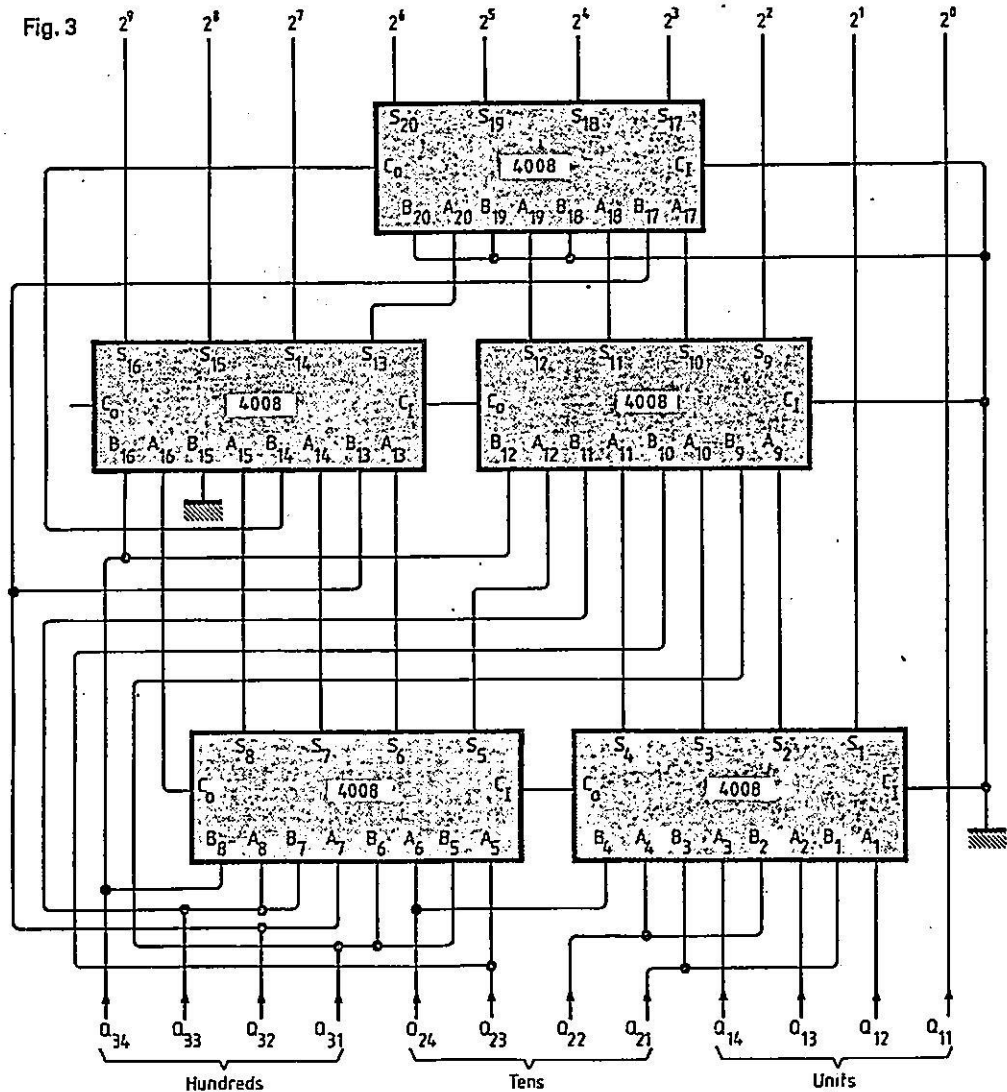


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A. J. Ewins
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RAM makes programmable digital delay circuit

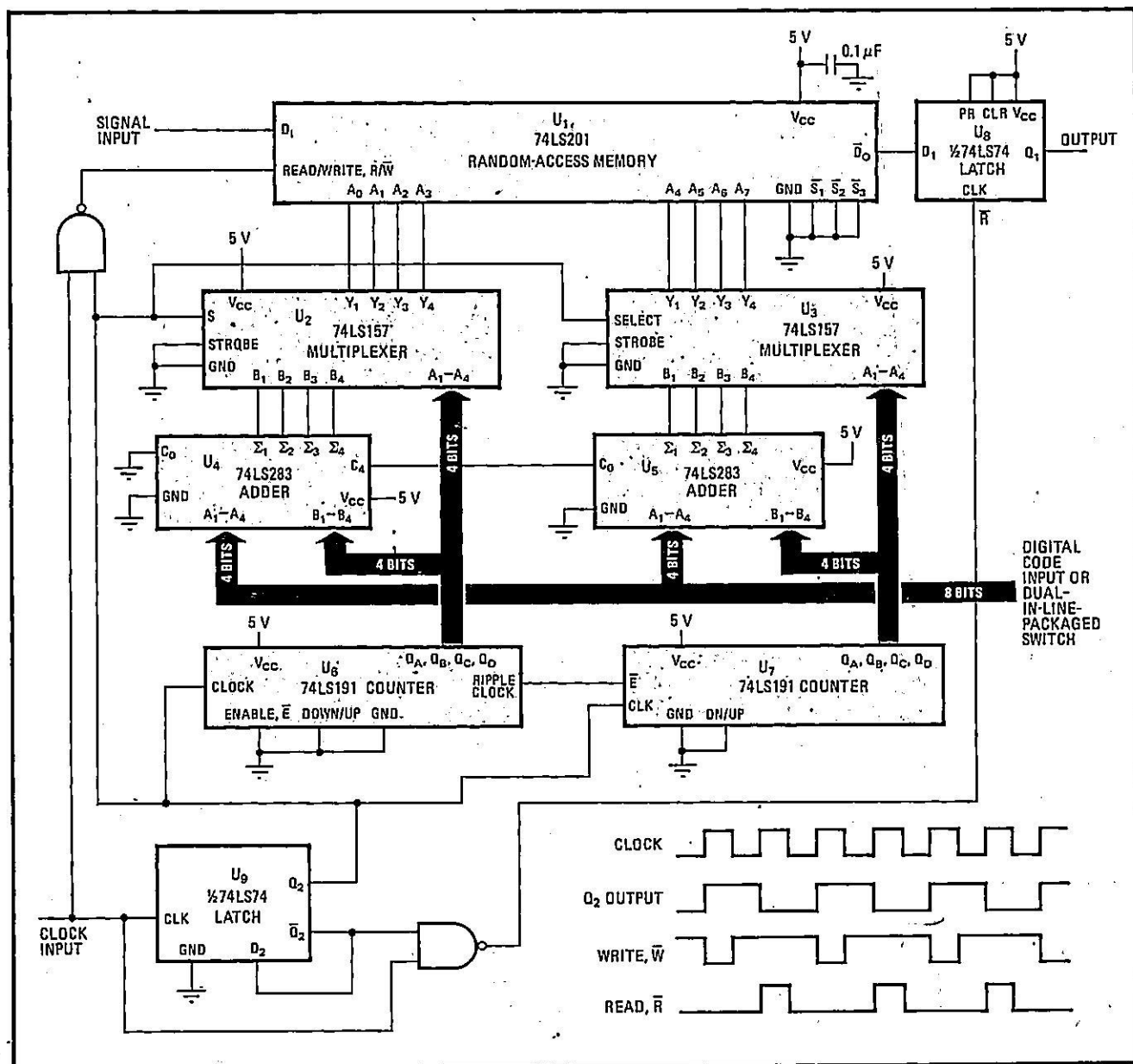
by Darius Vakili
Bayly Engineering, Ajax, Ont., Canada

For applications lacking in long shift registers and for which bipolar components are too expensive, this simple random-access-memory circuit will program the delay of digital signals precisely and accurately—and without needing varying clock frequencies. The RAM's ready availability and low cost add to the circuit's attractions, especially when high signal speeds are involved.

A digital input code programs the output delay of the

signal. The input signal is written into the RAM U_1 at an address generated by synchronous up-down counters U_6 and U_7 and by a fixed input digital code set by the dual-in-line-packaged switch. The stored signal is available at the output when the write-enable input to the RAM is high. This data is read out of the RAM from a location that corresponds to the address generated by the counters only. Therefore, the signal read from the RAM is delayed by a time period equal to the DIP switch's displacement value multiplied by the period of the clock used for generating the address.

The input clock is divided by 2 by latch U_9 . The Q_2 output of U_9 clocks address counters U_6 and U_7 and also the select inputs of multiplexers U_2 and U_3 . The NAND gates generate the RAM's read and write inputs and ensure the data is written into the RAM when the control input of U_2 and U_3 is high and read out when it is low. □



Programmed delay. Using random-access memory, this programmable-delay circuit accurately controls signal delay by means of a digital code generated by a DIP switch. Counters U_6 and U_7 generate the address for the RAM. U_9 provides the write and read inputs for the RAM.

Am2167

16,384 x 1 Static RAM

DISTINCTIVE CHARACTERISTICS

- High speed — access times as fast as 35ns maximum
- Automatic power down when deselected
- Low power dissipation
 - Am2167: 660mW active, 110mW power down
- High output drive
 - Up to seven standard TTL loads or six Schottky TTL loads
- TTL compatible interface levels
- No power-on current surge

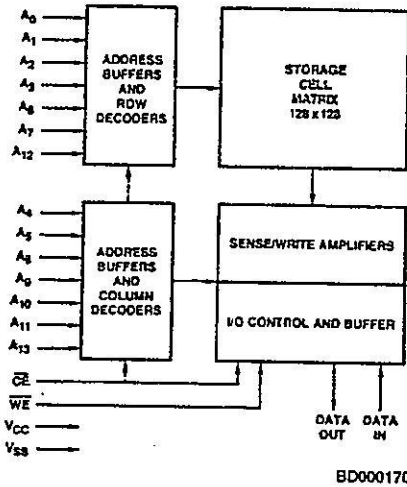
GENERAL DESCRIPTION

The Am2167 is a high performance, 16,384-bit, static, read/write, random access memory. It is organized as 16,384 words by one bit per word. All interface signal levels are identical to TTL specifications, providing good noise immunity and simplified system design. All inputs are purely capacitive MOS loads. The outputs will drive up to six standard Schottky TTL loads or up to seven standard TTL loads.

Only a single +5 volt power supply is required. When deselected ($CE \geq V_{IH}$), the Am2167 automatically enters a power-down mode which reduces power dissipation by 80%.

Data In and Data Out use separate pins and are the same polarity allowing them to be connected together for operation in a common data bus environment. Data Out is a three-state output allowing similar devices to be wire-OR'd together.

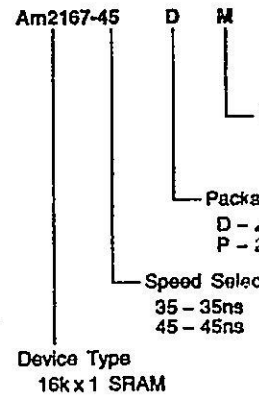
BLOCK DIAGRAM



PRODUCT SELECTOR GUIDE

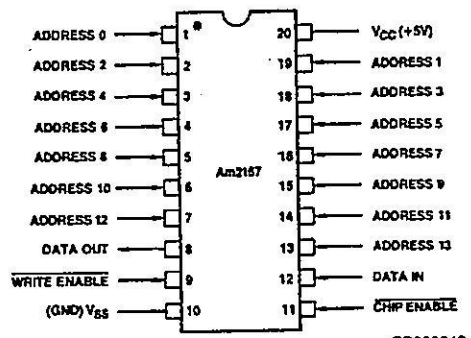
Part Number	Am2167-35	Am2167-45	Am2167-55	Am2167-70
Maximum Access Time (ns)	35	45	55	70
Maximum Active Current (mA)	120	120 (160 mil)	120 (160 mil)	120 (160 mil)
Maximum Standby Current (mA)	20	20 (30 mil)	20 (30 mil)	20 (30 mil)
Full Military Operating Range Version	No	Yes	Yes	Yes

Address Dec	External
A0	
A1	
A2	
A3	
A4	
A5	
A6	
A7	
A8	
A9	
A10	
A11	
A12	
A13	



CONNECTION DIAGRAM
Top View

D-20-1, P-20-1

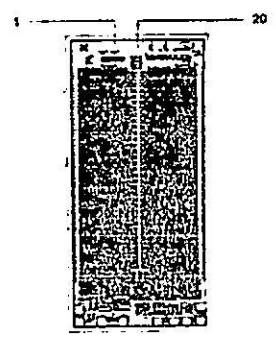


CD000240

Note: Pin 1 is marked for orientation

BIT MAP

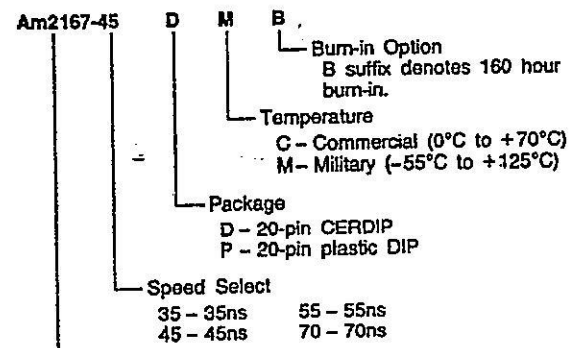
Address Designators	
External	Internal
A ₀	A ₁
A ₁	A ₆
A ₂	A ₂
A ₃	A ₅
A ₄	A ₃
A ₅	A ₀
A ₆	A ₄
A ₇	A ₁₃
A ₈	A ₁₀
A ₉	A ₈
A ₁₀	A ₁₁
A ₁₁	A ₉
A ₁₂	A ₁₂
A ₁₃	A ₇



DIE SIZE: 0.121 x 0.249

Figure 3. Bit Mapping Information

ORDERING INFORMATION



Valid Combinations	
Am2167-35	PC, DC
Am2167-45	PC, DC, DM, DMB
Am2167-55	PC, DC, DM, DMB
Am2167-70	PC, DC, DM, DMB

Device Type
16k x 1 SRAM

87-55	Am2167-70
5	70
(30 mil)	120 (160 mil)
(1 mil)	(20 (30 mil))
ps	Yes

03211D

03211D

ABSOLUTE MAXIMUM RATINGS

Storage Temperature	-65°C to +150°C
Ambient Temperature with Power Applied	-55°C to +125°C
Supply Voltage	-0.5V to +7.0V
Signal Voltages with respect to ground	-3.0V to +7.0V
Power Description	1.0W
DC Output Current	10mA

The products described by this specification include internal circuitry designed to protect input devices from damaging accumulations of static charge. It is suggested nevertheless, that conventional precautions be observed during storage, handling and use in order to avoid exposure to excessive voltages.

OPERATING RANGES

Commercial (C) Devices	Temperature	0°C to +70°C
	Supply Voltage	+4.5V to +5.5V
Military (M) Devices	Temperature	-65°C to +125°C
	Supply Voltage	+4.5V to +5.5V

Operating ranges define those limits over which the functionality of the device is guaranteed.

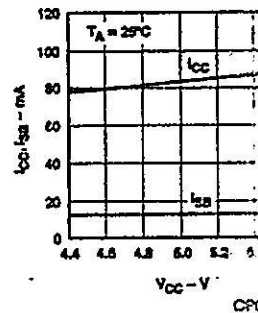
DC CHARACTERISTICS over operating range unless otherwise specified

Symbol	Parameter	Test Conditions	Am2167-35		Am2167-45 Am2167-55 Am2167-70		Units
			Min	Max	Min	Max	
I _{OH}	Output High Current	V _{OH} = 2.4V	V _{CC} = 4.5V		-4	-4	mA
I _{OL}	Output Low Current	V _{OL} = 0.4V	COM'L		16	16	mA
			MIL		12	12	
V _{IH}	Input High Voltage		2.0	6.0	2.0	6.0	Volts
V _{IL}	Input Low Voltage		-3.0	0.8	-3.0	0.8	Volts
I _{Ix}	Input Load Current	V _{SS} < V _I < V _{CC}		10		10	μA
I _{OZ}	Output Leakage Current	GND < V _O < V _{CC} Output Disabled	-50	50	-50	50	μA
C _I	Input Capacitance	Test Frequency = 1.0 MHz		5		5	pF
C _O	Output Capacitance	T _A = 25°C, All pins at 0V, V _{CC} = 5V		6		6	
I _{CC}	V _{CC} Operating Supply Current	Max V _{CC} , CE < V _{IL} Output Open	COM'L		120	120	mA
			MIL		N/A	160	
I _{SB}	Automatic CE Power Down Current	MAX V _{CC} , (CE > V _{IH}) (Note 3)	COM'L		20	20	mA
			MIL		N/A	30	

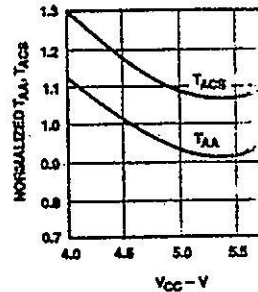
Notes:

- Test conditions assume signal transition times of 5ns or less, timing reference levels of 1.5V, input pulse levels of 0 to 3.0V and output loading of the specified I_{OL}/I_{OH} and 30pF load capacitance. Output timing reference is 1.5V.
- The internal write time of the memory is defined by the overlap of CE low and WE low. Both signals must be low to initiate a write and either signal can terminate a write by going high. The data input setup and hold timing should be referenced to the rising edge of the signal that terminates the write.
- A pull-up resistor to V_{CC} on the CE input is required to keep the device deselected during V_{CC} power up. Otherwise I_{SB} will exceed values given.
- The operating ambient temperature range is guaranteed with transverse air flow of 400 linear feet per minute.
- The device must be selected during the previous cycle. Otherwise t_{AA} and t_{CS} are equivalent to t_{ACS}.
- At any given temperature and voltage condition, t_{HZ} is less than t_{LZ} for all devices. Transition is measured ±500mV from steady state voltage with load specified in Figure 2 for t_{HZ}, t_{LZ}, t_{OW} and t_{WZ}.
- WE is high for read cycle.
- Address valid prior to or coincident with CE transition low.

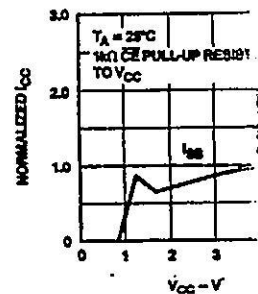
Supply Current versus Supply Voltage



Normalized Access Time versus Supply Voltage



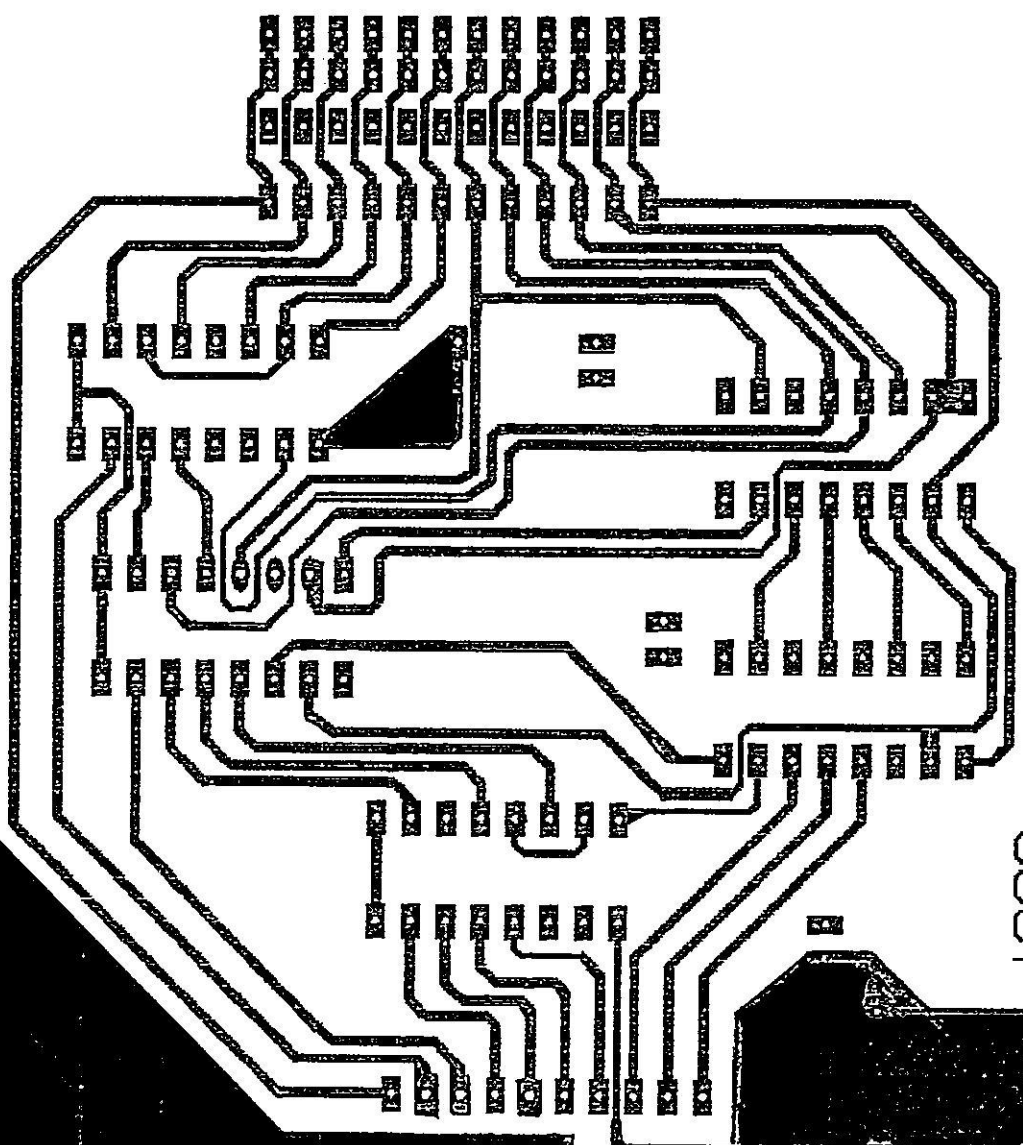
Typical Power-On Current versus Power Supply



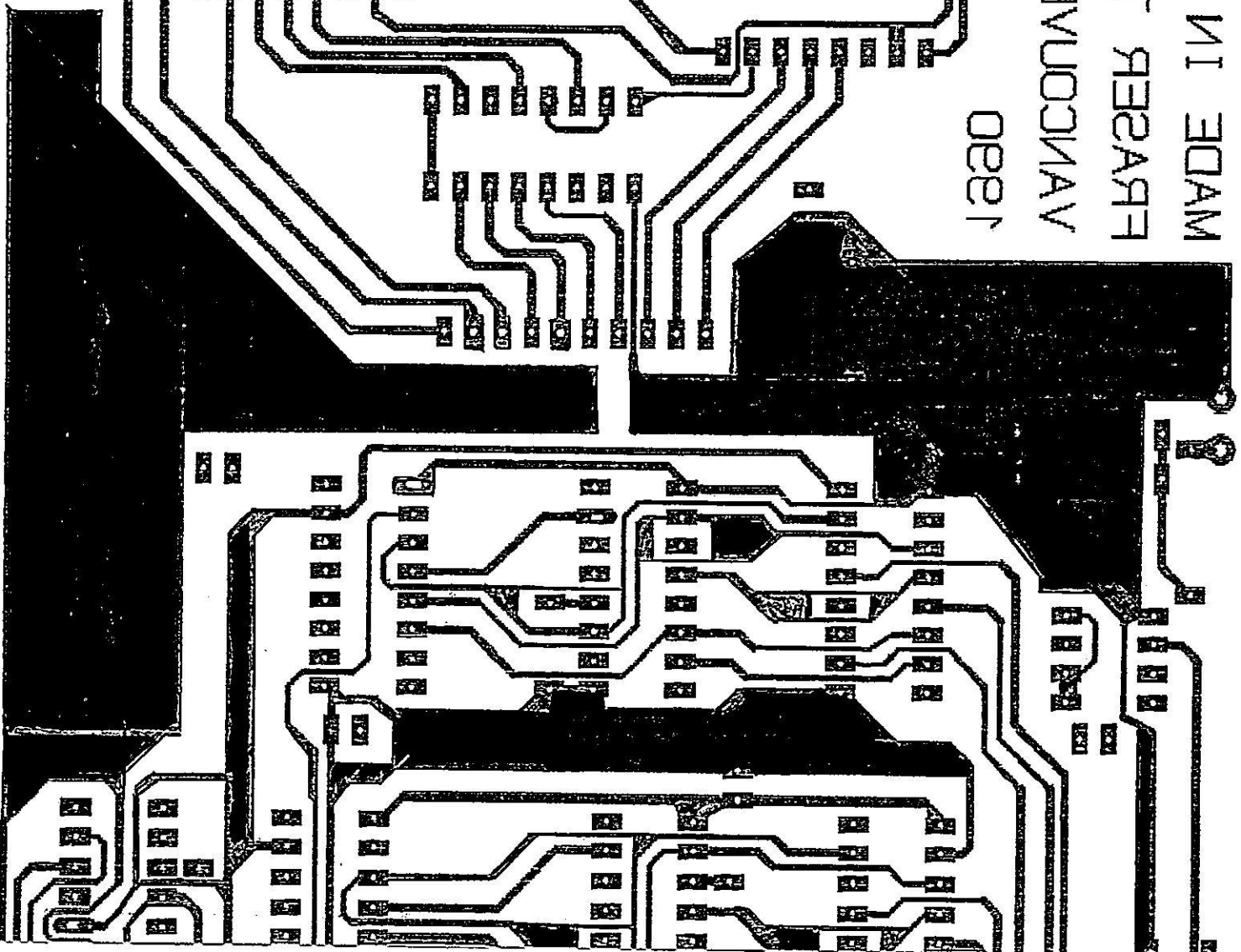


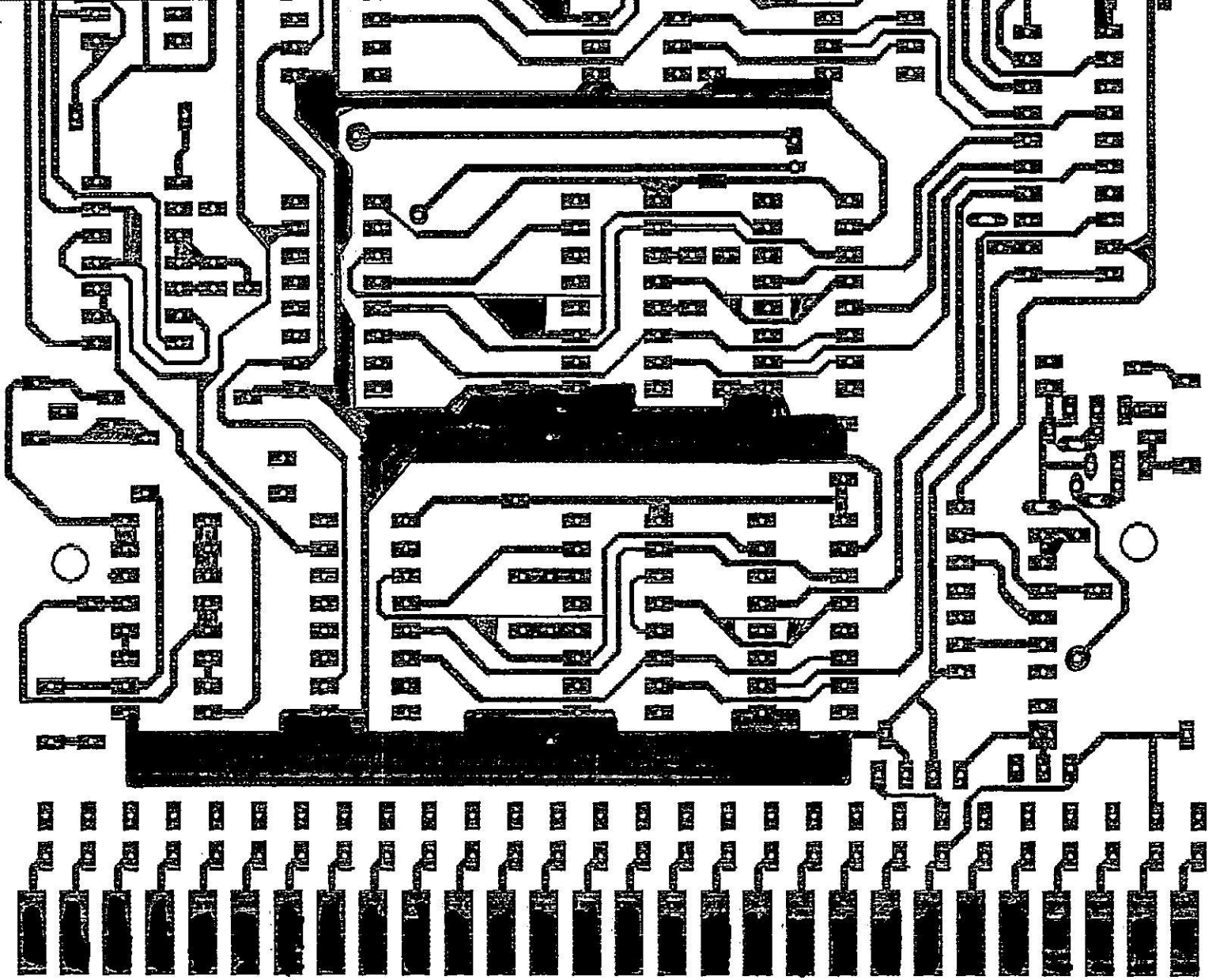
ADAMAS NI EDAM
.DTJ .HDET REZAPF
.J.B .REYUODIAY

DEER



DELAY TIME
PROGRAMMABLE





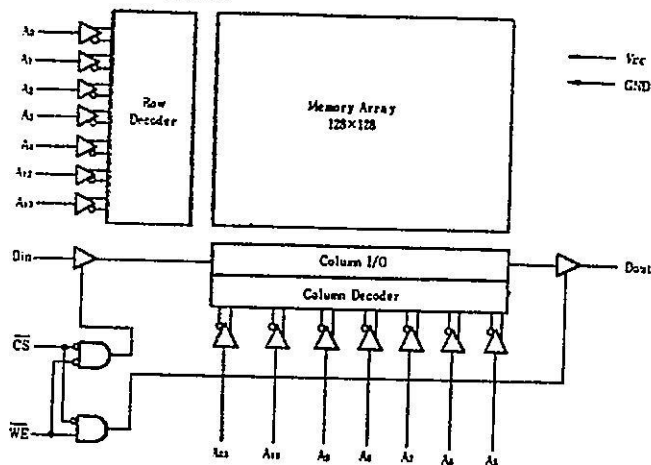
HM6167, HM6167-6, HM6167-8, HM6167P, HM6167P-6, HM6167P-8

16384-word × 1-bit High Speed Static CMOS RAM

FEATURES

- Single +5V Supply and High Density 20 Pin Package
- Fast Access Time – 70ns/85ns/100ns
- Low Power Stand-by and Low Power Operation
Stand-by 25mW Typ. and Operating 150mW Typ.
- Completely Static Memory No Clock nor Refresh Required
- Fully TTL Compatible – All Inputs and Output
- Separate Data Input and Output Three State Output
- Pin-Out Compatible with Intel 2167 Series

BLOCK DIAGRAM



ABSOLUTE MAXIMUM RATINGS

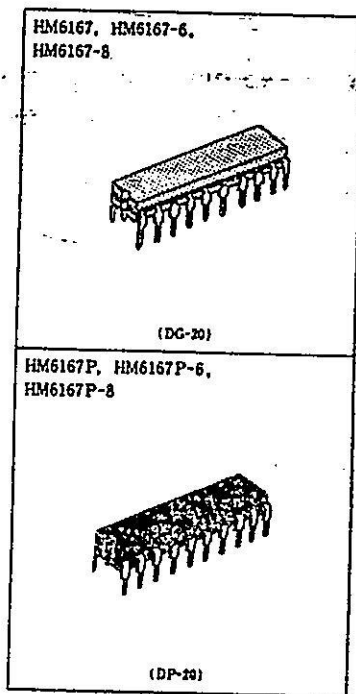
Item	Symbol	Rating	Unit
Terminal Voltage with Respect to GND	V_T	-0.5* to +7.0	V
Power Dissipation	P_T	1.0	W
Operating Temperature	T_{OP}	0 to +70	°C
Storage Temperature (Plastic)	T_{stg}	-55 to +125	°C
Storage Temperature (Ceramic)	T_{stg}	-65 to +150	°C
Storage Temperature**	$T_{stg(max)}$	-10 to +85	°C

* Pulse width 20ns : -3.5V ** solder bias

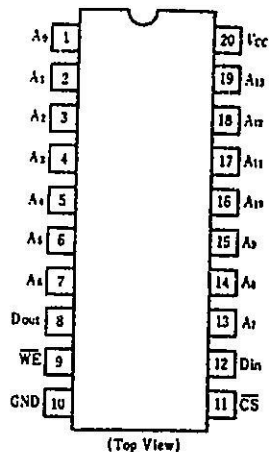
RECOMMENDED DC OPERATING CONDITIONS (0°C ≤ T_a ≤ 70°C)

Item	Symbol	min	typ	max	Unit
Supply Voltage	V_{CC}	4.5	5.0	5.5	V
	GND	0	0	0	V
Input High Voltage	V_{IH}	2.2	—	6.0	V
Input Low Voltage	V_{IL}	-3.0*	—	0.8	V

* Pulse width 20ns, DC : $V_{IL, min} = -3.1V$



PIN ARRANGEMENT



EG- delay = 1000 ns

1. Counter = 0000

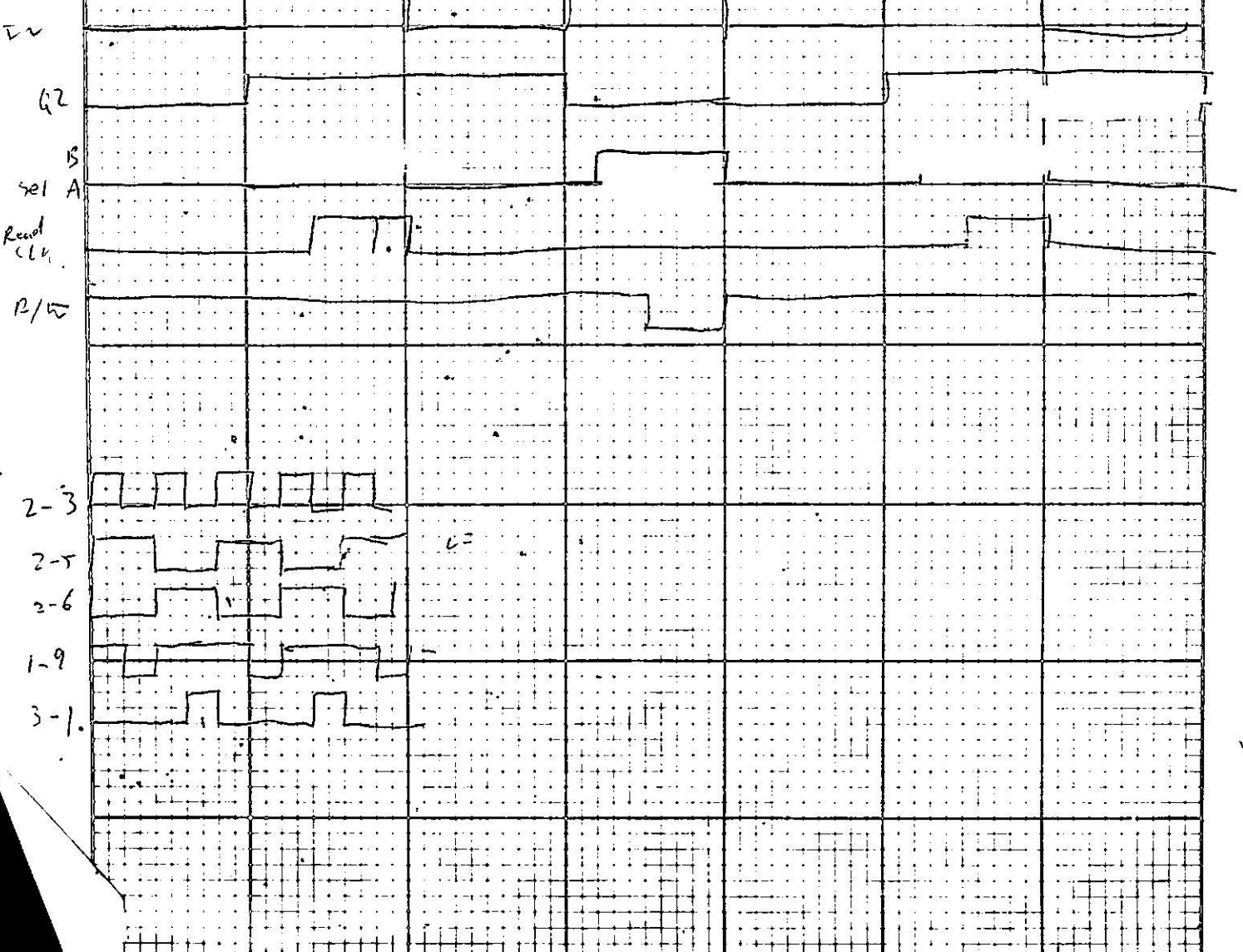
2. Address output = 1000

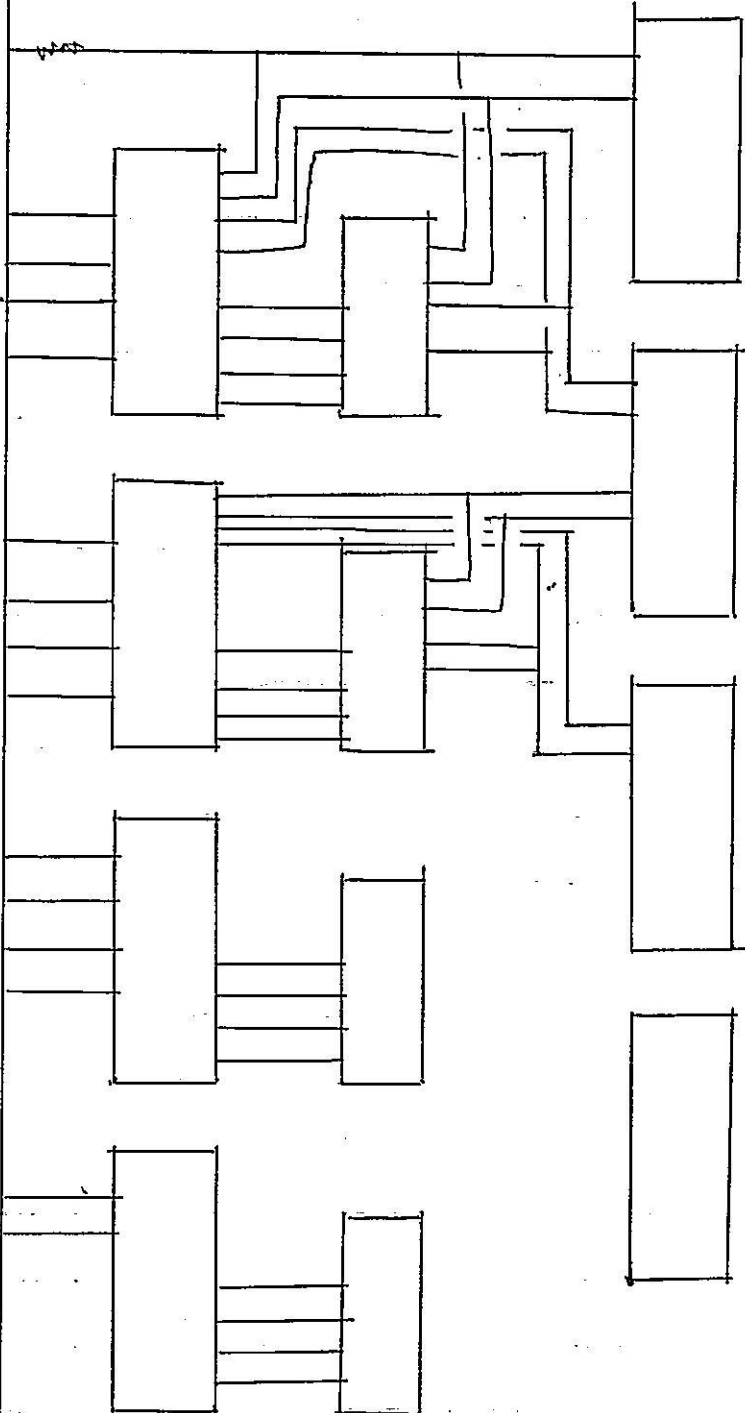
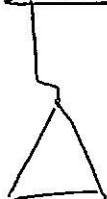
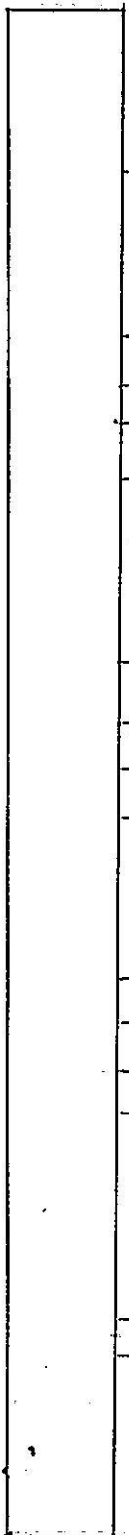
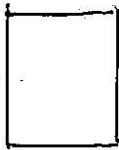
3. Read Data 1000s After Clock Input

4. At 500ns select write and ~~sample~~ ^{sample} counter

5. At 600ns pull R/W Low to write to 250.45

100ns





1. 20
2. 1. 20
3. 1. 20

